

Search Notes

Application/Control No.

10/725,523

Examiner

Stephen W. Smoot

Applicant(s)/Patent under
Reexamination

WU, BING-CHANG

Art Unit

2813

SEARCHED

Class	Subclass	Date	Examiner
438	300	3/15/2005	SWS
438	479, 481	3/15/2005	SWS
438	500, 502	3/15/2005	SWS
438	507, 509	3/15/2005	SWS
438	592	3/15/2005	SWS
438	607	3/15/2005	SWS
438	649	3/15/2005	SWS
438	655	3/15/2005	SWS
438	682, 683	3/15/2005	SWS
438	738	3/15/2005	SWS
438	753	3/15/2005	SWS

*S.W.S.***INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Key Words: Epitaxial Layer; Silicide; Selective - Etching, Removal;	3/15/2005	<i>S.W.S.</i> SWS
Heating, Annealing, Rapid Thermal Process - RTP, RTA.	3/15/2005	<i>S.W.S.</i> SWS
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	3/15/2005	<i>S.W.S.</i> SWS